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1	(test\$5 burn\$4 stress\$4) with (high\$4 max\$6 exceed\$4) with operat\$5 with voltage and (test\$5 burn\$4 stress\$4) with (low\$4 below abnormal) with operat\$5 with voltage and (test\$5 burn\$4 stress\$4) with wafer and @ad<"20040115"
2	(test\$5 burn\$4 stress\$4) with (high\$4 max\$6 exceed\$4) with operat\$5 with voltage and (test\$5 burn\$4 stress\$4) with (low\$4 below abnormal) with operat\$5 with voltage and (test\$5 burn\$4 stress\$4) with wafer and @ad<"20040115" and (determin\$5 idendif\$6 select\$5 find\$4) with (best optim\$7) with operat\$5 with voltage
3	(test\$5 burn\$4 stress\$4) with (high\$4 max\$6 exceed\$4) with (working operat\$5) with voltage and (test\$5 burn\$4 stress\$4) with (low\$4 below abnormal) with (working operat\$5) with voltage and (test\$5 burn\$4 stress\$4) with wafer and @ad<"20040115" and (determin\$5 idendif\$6 select\$5 find\$4) with (best optim\$7) with (working operat\$5) with voltage